

Title (en)
METHOD FOR EVALUATING THE QUALITY OF THE MEASUREMENT OF A WAVEFRONT AND SYSTEMS IMPLEMENTING SUCH A METHOD

Title (de)
VERFAHREN ZUR BEWERTUNG DER QUALITÄT DER MESSUNG EINER WELLENFRONT UND SYSTEME ZUR IMPLEMENTIERUNG SOLCH EINES VERFAHRENS

Title (fr)
MÉTHODE D'ÉVALUATION DE LA QUALITÉ DE LA MESURE D'UN FRONT D'ONDE ET SYSTÈMES METTANT EN OEUVRE UNE TELLE MÉTHODE

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Application
EP 18704888 A 20180126

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Abstract (en)
[origin: WO2018138269A1] The present description relates according to one aspect to a method for evaluating the quality of the measurement of an optical wavefront, said measurement being obtained by means of a wavefront analyser by direct measurement, the method comprising: the acquisition (10) of an optoelectronic signal for the measurement of the wavefront by means of a wavefront sensor, said sensor comprising a two-dimensional detector; the determination (11) on the basis of said optoelectronic signal of a parameter characteristic of a parasitic component of the optoelectronic signal; the evaluation (12) of a quality factor of the measurement of the wavefront as a function of said at least one parameter characteristic of the parasitic component of the signal; the display (13) of a level of quality of the measurement destined for a user as a function of said quality factor.

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